

**Notice of References Cited**Application/Control No.  
10/029,476Applicant(s)/Patent Under  
Reexamination  
LAMPAERT ET AL.Examiner  
Leigh Marie GarbowskiArt Unit  
2825

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,381,563 B1	04-2002	O'Riordan et al.	703/14
	B	US-5,666,288	09-1997	Jones et al.	716/17
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ferrario et al., "Moving from Mixed Signal to RF Test Hardware Development," 2001 ITC Int'l Test Conference, Paper 34.1, pages 948-956.
	V	Miliozzi et al., "A Design System for RFIC: Challenges and Solutions," Proceedings of the IEEE, Vol. 88, No. 10, October 2000, pages 1613-1632.
	W	Charbon et al., "Generalized Constraint Generation for Analog Circuit Design," 1993 IEEE/ACM Int'l Conference on CAD, pages 408-414.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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